# **Power MOSFET**

# 30 V, 170 A, Single N-Channel, μ8FL

#### **Features**

- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

### **Applications**

- DC-DC Converters
- Power Load Switch
- Notebook Battery Management

### MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise stated)

Param	Symbol	Value	Unit		
Drain-to-Source Voltage	$V_{DSS}$	30	V		
Gate-to-Source Voltage	$V_{GS}$	±20	V		
Continuous Drain		T <sub>A</sub> = 25°C	I <sub>D</sub>	29	Α
Current R <sub>θJA</sub> (Note 1)		T <sub>A</sub> = 85°C	1	21	
Power Dissipation $R_{\theta JA}$ (Note 1)		T <sub>A</sub> = 25°C	P <sub>D</sub>	2.7	W
Continuous Drain		T <sub>A</sub> = 25°C	I <sub>D</sub>	36	Α
Current R <sub>θJA</sub> ≤ 10 s (Note 1)		T <sub>A</sub> = 85°C	1	26	
Power Dissipation $R_{\theta JA} \le 10 \text{ s (Note 1)}$	Steady	T <sub>A</sub> = 25°C	P <sub>D</sub>	4.2	W
Continuous Drain	State	T <sub>A</sub> = 25°C	I <sub>D</sub>	16	Α
Current R <sub>θJA</sub> (Note 2)		T <sub>A</sub> = 85°C	1	12	
Power Dissipation R <sub>θJA</sub> (Note 2)		T <sub>A</sub> = 25°C	P <sub>D</sub>	0.83	W
Continuous Drain		T <sub>C</sub> = 25°C	I <sub>D</sub>	170	Α
Current R <sub>θJC</sub> (Note 1)		T <sub>C</sub> = 85°C	1	120	
Power Dissipation $R_{\theta JC}$ (Note 1)		T <sub>C</sub> = 25°C	P <sub>D</sub>	91	W
Pulsed Drain Current	I <sub>DM</sub>	500	Α		
Operating Junction and S	T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C		
Source Current (Body Die	IS	100	Α		
Drain to Source dV/dt	dV/dt	6.0	V/ns		
Single Pulse Drain-to-So (I <sub>L</sub> = 37 A <sub>pk</sub> ) (Note 3)	E <sub>AS</sub>	162	mJ		
Lead Temperature for So (1/8" from case for 10 s)	TL	260	°C		

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
   Surface-mounted on FR4 board using the minimum recommended pad size.
- 3. This is the absolute maximum ratings. Parts are 100% tested at  $T_{\perp} = 25^{\circ}$ C,  $V_{GS} = 10 \text{ V}, I_L = 36 \text{ A}, E_{AS} = 65 \text{ mJ}.$

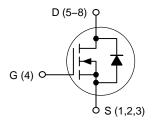


### ON Semiconductor®

#### www.onsemi.com

V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub> MAX	I <sub>D</sub> MAX	
30 V	2.25 mΩ @ 10 V	170 A	
	3.1 mΩ @ 4.5 V	1707	

#### **N-Channel MOSFET**





#### **MARKING DIAGRAM** þо D D s t S AYWW= þο G þρ

4C02 = Specific Device Code = Assembly Location Α

= Year WW = Work Week = Pb-Free Package

(Note: Microdot may be in either location)

#### ORDERING INFORMATION

Device	Package	Shipping <sup>†</sup>		
NTTFS4C02NTAG	WDFN8 (Pb-Free)	1500 / Tape & Reel		

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{\theta JC}$	1.4	
Junction-to-Ambient - Steady State (Note 4)	$R_{\theta JA}$	46	°C/W
Junction-to-Ambient - Steady State (Note 5)	$R_{\theta JA}$	150	*C/vv
Junction–to–Ambient – (t ≤ 10 s) (Note 4)	$R_{\theta JA}$	30	

- 4. Surface–mounted on FR4 board using 1 sq-in pad, 1 oz Cu.5. Surface–mounted on FR4 board using the minimum recommended pad size.

### **ELECTRICAL CHARACTERISTICS** (T<sub>.1</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> / T <sub>J</sub>				13.8		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{GS} = 0 \text{ V},$ $V_{DS} = 24 \text{ V}$	T <sub>J</sub> = 25°C			1.0	
		$V_{DS} = 24 \text{ V}$	T <sub>J</sub> = 125°C			10	μΑ
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 30 V	T <sub>J</sub> = 25°C			10	μΑ
Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS}$	s = 20 V			100	nA
ON CHARACTERISTICS (Note 6)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D$	= 250 μΑ	1.3	1.6	2.2	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				5.0		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 20 A		1.9	2.25	0
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 20 A		2.7	3.1	mΩ
Forward Transconductance	9FS	V <sub>DS</sub> = 1.5 V, I <sub>D</sub> = 50 A			140		S
Gate Resistance	$R_{G}$				0.9		Ω
CHARGES AND CAPACITANCES							
Input Capacitance	C <sub>ISS</sub>				2980		
Output Capacitance	C <sub>OSS</sub>	$V_{GS} = 0 \text{ V, f} = 1 \text{ MHz, V}_{DS} = 15 \text{ V}$			1200		pF
Reverse Transfer Capacitance	C <sub>RSS</sub>				55		
Output Charge	Q <sub>OSS</sub>	V <sub>GS</sub> = 0 V, V <sub>DD</sub> = 15 V			25		nC
Capacitance Ratio	C <sub>RSS</sub> /C <sub>ISS</sub>	$V_{GS} = 0 \text{ V}, V_{DS} = 15$	V, f = 1 MHz		0.018		
Total Gate Charge	Q <sub>G(TOT)</sub>				20		
Threshold Gate Charge	Q <sub>G(TH)</sub>				4.7		,,C
Gate-to-Source Charge	$Q_{GS}$	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V}; I_D = 50 \text{ A}$			8.5		nC
Gate-to-Drain Charge	$Q_{GD}$				4		
Gate Plateau Voltage	$V_{GP}$				2.8		V
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 15 V; I <sub>D</sub> = 50 A			45		nC
SWITCHING CHARACTERISTICS (Note 7)							
Turn-On Delay Time	t <sub>d(ON)</sub>	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V},$ $I_{D} = 50 \text{ A}, R_{G} = 3.0 \Omega$			12		
Rise Time	t <sub>r</sub>				116		
Turn-Off Delay Time	t <sub>d(OFF)</sub>				25		ns
Fall Time	t <sub>f</sub>				10		

- 6. Pulse Test: pulse width  $\leq 300~\mu s$ , duty cycle  $\leq 2\%$ .
  7. Switching characteristics are independent of operating junction temperatures.

## **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS (N	ote 7)					•	
Turn-On Delay Time	t <sub>d(ON)</sub>			9		ns ns	
Rise Time	t <sub>r</sub>	$V_{GS} = 10 \text{ V}, V_{DS} = 15 \text{ V},$ $I_{D} = 50 \text{ A}, R_{G} = 3.0 \Omega$			102		
Turn-Off Delay Time	t <sub>d(OFF)</sub>				33		
Fall Time	t <sub>f</sub>				6		
DRAIN-SOURCE DIODE CHARACT	ERISTICS						
Forward Diode Voltage	$V_{SD}$	VGS = 0 V,	T <sub>J</sub> = 25°C		0.8	1.1	
			T <sub>J</sub> = 125°C		0.6		V
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V, } dI_{S}/dt = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 50 \text{ A}$			42		
Charge Time	t <sub>a</sub>				21		ns
Discharge Time	t <sub>b</sub>				21		
Reverse Recovery Charge	$Q_RR$				28		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

<sup>6.</sup> Pulse Test: pulse width  $\leq 300~\mu s$ , duty cycle  $\leq 2\%$ .
7. Switching characteristics are independent of operating junction temperatures.

#### **TYPICAL CHARACTERISTICS**

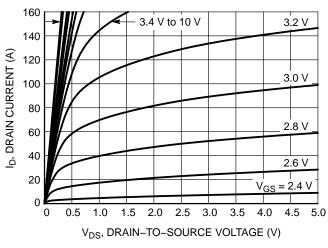


Figure 1. On-Region Characteristics

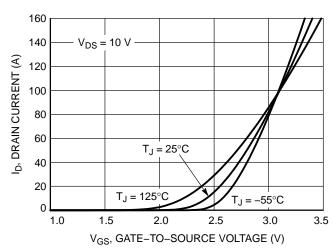


Figure 2. Transfer Characteristics

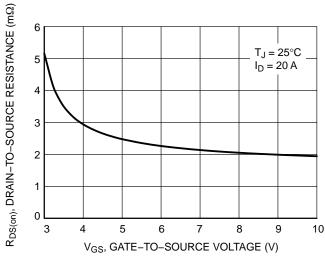


Figure 3. On–Resistance vs. Gate–to–Source Voltage

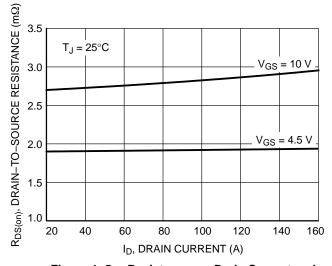


Figure 4. On–Resistance vs. Drain Current and Gate Voltage

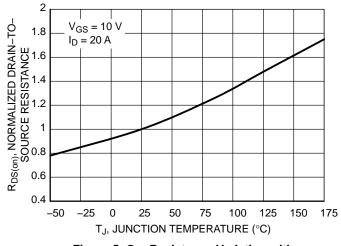


Figure 5. On–Resistance Variation with Temperature

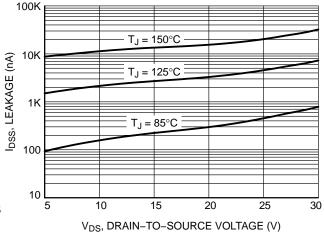
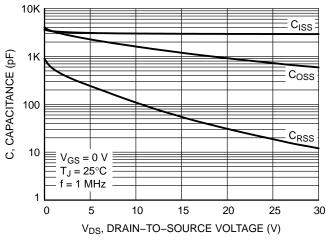


Figure 6. Drain-to-Source Leakage Current vs. Voltage

#### **TYPICAL CHARACTERISTICS**

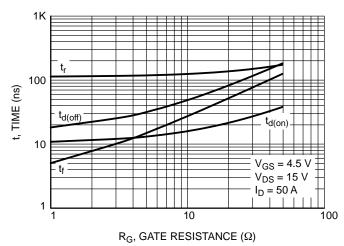
5



V<sub>GS</sub>, GATE-TO-SOURCE VOLTAGE (V) 4 **⊄**Q<sub>GD</sub>  $\mathsf{Q}_{\mathsf{GS}}$ 3 2  $V_{DS} = 15 \text{ V}$  $T_J = 25^{\circ}C$  $I_{D} = 50 \text{ A}$ 10 12 16 Q<sub>G</sub>, TOTAL GATE CHARGE (nC)

Figure 7. Capacitance Variation

Figure 8. Gate-to-Source vs. Total Charge



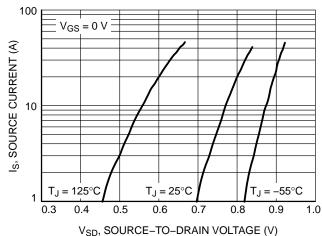
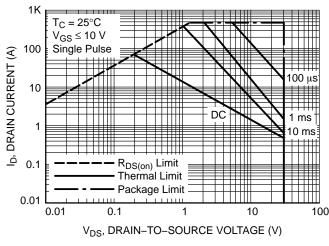


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

Figure 10. Diode Forward Voltage vs. Current



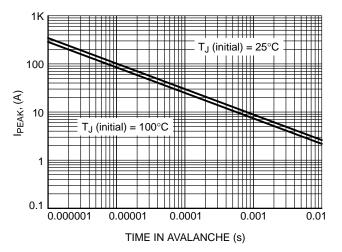


Figure 11. Maximum Rated Forward Biased Safe Operating Area

Figure 12. I<sub>PEAK</sub> vs. Time in Avalanche

# **TYPICAL CHARACTERISTICS**

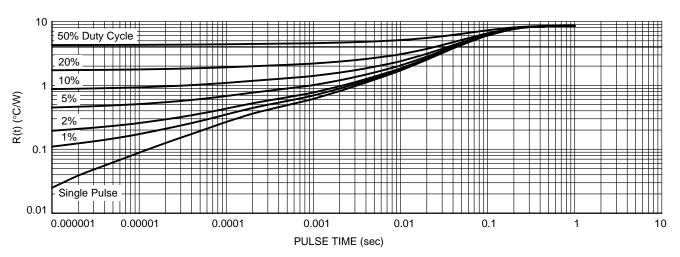
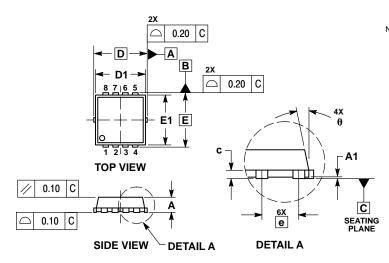


Figure 13. Thermal Characteristics

#### PACKAGE DIMENSIONS

#### WDFN8 3.3x3.3, 0.65P CASE 511AB ISSUE D



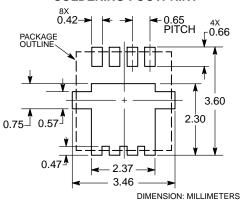
#### NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
   CONTROLLING DIMENSION: MILLIMETERS.
- DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE BURRS

	MI	LLIMETE	RS	INCHES			
DIM	MIN	NOM	MAX	MIN	NOM	MAX	
Α	0.70	0.75	0.80	0.028	0.030	0.031	
A1	0.00		0.05	0.000		0.002	
b	0.23	0.30	0.40	0.009	0.012	0.016	
С	0.15	0.20	0.25	0.006	0.008	0.010	
D		3.30 BSC		0.130 BSC			
D1	2.95	3.05	3.15	0.116	0.120	0.124	
D2	1.98	2.11	2.24	0.078	0.083	0.088	
E		3.30 BSC		0.130 BSC			
E1	2.95	3.05	3.15	0.116	0.120	0.124	
E2	1.47	1.60	1.73	0.058	0.063	0.068	
E3	0.23	0.30	0.40	0.009	0.012	0.016	
е		0.65 BSC	;	(	0.026 BS0	3	
G	0.30	0.41	0.51	0.012	0.016	0.020	
K	0.65	0.80	0.95	0.026	0.032	0.037	
L	0.30	0.43	0.56	0.012	0.017	0.022	
L1	0.06	0.13	0.20	0.002	0.005	0.008	
M	1.40	1.50	1.60	0.055	0.059	0.063	
θ	0 °		12 °	0 °		12 °	

# С В 0.10 Α 0.05 С **E**3 D2 G **BOTTOM VIEW**

#### **SOLDERING FOOTPRINT\***



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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